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**Ralf Widenhorn
Valérie Nguyen**
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Contents

vii *Conference Committee*

SESSION 1 COLOR AND MULTISPECTRAL TECHNIQUES

- 7875 02 **Single-chip color imaging for UHD TV camera with a 33M-pixel CMOS image sensor** [7875-01]
R. Funatsu, T. Yamashita, NHK Science & Technology Research Labs. (Japan); K. Mitani, NHK (Japan); Y. Nojiri, NHK Science & Technology Research Labs. (Japan)
- 7875 03 **Spatial arrangement of color filter array for multispectral image acquisition** [7875-02]
R. Shrestha, J. Y. Hardeberg, R. Khan, Gjøvik Univ. College (Norway)
- 7875 04 **Spectral-based calorimetric calibration of a 3CCD color camera for fast and accurate characterization and calibration of LCD displays** [7875-03]
R. Safaee-Rad, Qualcomm Inc. (Canada); M. Aleksic, Qualcomm Inc. (United States)

SESSION 2 ADVANCED CAMERA SYSTEMS I

- 7875 05 **Optimizing quantum efficiency in a stacked CMOS sensor** [7875-04]
R. Hannebauer, Lumiense Photonics, Inc. (Canada); S. K. Yoo, HanVision Co. Ltd. (Korea, Republic of); D. L. Gilblom, A. D. Gilblom, Alternative Vision Corp. (United States)
- 7875 07 **Detailed characterisation of a new large area CCD manufactured on high resistivity silicon** [7875-06]
M. S. Robbins, P. Mistry, P. R. Jordan, e2v technologies Ltd. (United Kingdom)
- 7875 08 **Simulating enhanced photo carrier collection in the multifinger photogate active pixel sensors** [7875-07]
P. Kalyanam, G. H. Chapman, A. M. Parameswaran, Simon Fraser Univ. (Canada)

SESSION 3 ADVANCED CAMERA SYSTEMS II

- 7875 0B **Correcting distortion and braiding of micro-images from multi-aperture imaging systems** [7875-10]
A. Oberdörster, A. Brückner, F. C. Wippermann, A. Bräuer, Fraunhofer Institute for Optics and Precision Engineering (Germany)
- 7875 0C **An analog logarithmic number system subtractor for edge detection in logarithmic CMOS image sensors** [7875-11]
D. R. Desai, The Univ. of Akron (United States); F. H. Hassan, Ohio Northern Univ. (United States); R. J. Veillette, J. E. Carletta, The Univ. of Akron (United States)

SESSION 4 APPLICATIONS

- 7875 0D **A CMOS image sensor with draining only modulation pixels for fluorescence lifetime imaging** [7875-12]
Z. Li, K. Yasutomi, T. Takasawa, S. Itoh, S. Kawahito, Shizuoka Univ. (Japan)
- 7875 0E **Development of biosensor based on imaging ellipsometry and its applications** [7875-14]
G. Jin, Institute of Mechanics (China)

SESSION 5 NOISE

- 7875 0G **Ageing effects on image sensors due to terrestrial cosmic radiation** [7875-16]
G. G. Nampoothiri, Technische Univ. Delft (Netherlands); M. L. R. Horemans, Consultant (Belgium); A. J. P. Theuwissen, Technische Univ. Delft (Netherlands) and Harvest Imaging (Belgium)
- 7875 0H **Nonlinear time dependence of dark current in charge-coupled devices** [7875-17]
J. C. Dunlap, E. Bodegom, R. Widenhorn, Portland State Univ. (United States)
- 7875 0I **Tradeoffs in imager design parameters for sensor reliability** [7875-18]
G. H. Chapman, J. Leung, R. Thomas, Simon Fraser Univ. (Canada); Z. Koren, I. Koren, Univ. of Massachusetts Amherst (United States)
- 7875 0J **Dark noise in a CMOS imager pixel with negative bias on transfer gate** [7875-19]
H. Yamashita, M. Maeda, S. Furuya, T. Yagami, Toshiba Corp. (Japan)

SESSION 6 SINGLE PHOTON DETECTION

- 7875 0L **The evolution of the scientific CCD (Invited Paper)** [7875-21]
M. M. Blouke, Portland State Univ. (United States)
- 7875 0M **3D ranging with a single-photon imaging array** [7875-22]
S. Bellisai, F. Guerrieri, Politecnico di Milano (Italy); S. Tisa, Micro Photon Devices S.r.l. (Italy); F. Zappa, Politecnico di Milano (Italy) and Micro Photon Devices S.r.l. (Italy)
- 7875 0N **Linear arrays of single-photon detectors for photon counting and timing** [7875-23]
F. Guerrieri, Politecnico di Milano (Italy); S. Tisa, Micro Photon Devices S.r.l. (Italy); A. Tosi, S. Bellisai, B. Markovic, Politecnico di Milano (Italy); F. Zappa, Politecnico di Milano (Italy) and Micro Photon Devices S.r.l. (Italy)
- 7875 0O **Single-photon sensitive fast ebCMOS camera system for multiple-target tracking of single fluorophores: application to nano-biophotonics** [7875-24]
T. Cajgfinger, E. Chabanat, A. Dominjon, Q. T. Doan, C. Guerin, J. Houles, R. Barbier, IPNL, CNRS, Univ. de Lyon (France)
- 7875 0P **Monolithic single-photon detectors and time-to-digital converters for picoseconds time-of-flight ranging** [7875-25]
B. Markovic, Politecnico di Milano (Italy); S. Tisa, Micro Photon Devices S.r.l. (Italy); A. Tosi, F. Zappa, Politecnico di Milano (Italy)

7875 0Q **Human-technology interaction for standoff IED detection** [7875-30]
E. Zhang, Y. Zou, L. Zachrich, EYZtek, Inc. (United States); J. Fulton, Navy Crane Base (United States)

SESSION 7 INTERACTIVE PAPER SESSION

7875 0R **Approach to quantitative detection of CD146 with the label-free protein biosensor based on imaging ellipsometry** [7875-26]
Y. Niu, L. Liu, Institute of Mechanics (China) and Graduate Univ. of the Chinese Academy of Sciences (China); X. Yan, Institute of Biophysics (China); G. Jin, Institute of Mechanics (China)

7875 0S **Dynamic range extension of a CMOS active pixel sensor by in-pixel charge mixing** [7875-27]
S.-H. Jo, M. Bae, J.-S. Kong, J.-K. Shin, Kyungpook National Univ. (Korea, Republic of)

7875 0T **A novel 3D architecture for high dynamic range image sensor and on-chip data compression** [7875-28]
F. Guezzi-Messaoud, A. Dupret, A. Peizerat, CEA LETI (France); Y. Blanchard, ESYCOM Lab., CNRS, Paris-Est Univ. (France)

7875 0U **Total internal reflection imaging ellipsometry (TIRIE) biosensor sensitivity improvement with low noise imaging device** [7875-29]
L. Liu, G. Jin, Institute of Mechanics (China)

Author Index

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- 1 Color and Multispectral Techniques
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- 2 Advanced Camera Systems I
Ralf Widenhorn, Portland State University (United States)
- 3 Advanced Camera Systems II
Ralf Widenhorn, Portland State University (United States)

- 4 Applications
Antoine Dupret, CEA Leti MINATEC (France)
- 5 Noise
Morley M. Blouke, Portland State University (United States)
- 6 Single Photon Detection
Erik Bodegom, Portland State University (United States)